

60V 2.8mohm N-channel SGT MOSFET AKG6N028GL

Description:

This N channel SGT MOSFET has been designed to very low on-state resistance and maintain superior switching performance, especial for high efficiency power management applications.

Features:

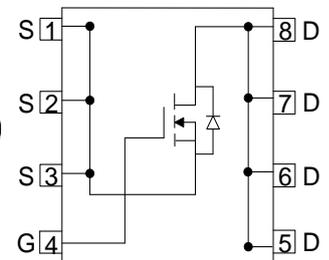
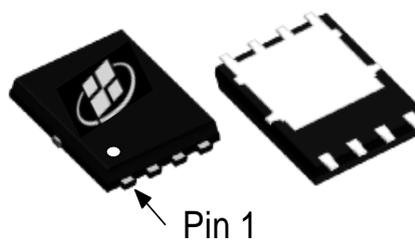
- LOW $R_{DS(ON)}$
- RoHS compliant ^(Note 1)
- Halogen-free ^(Note 1)

Applications:

- Battery Management System
- Motor Drivers
- DC-DC Converter

Key Performance Parameters:

Parameter	Value	Unit
V_{DS}	60	V
$R_{DS(ON), max} @ V_{GS} = 10V$	2.8	m Ω
I_D	100	A



Ordering Information:

Ordering Code	Package Type	Marking Code	Form	Packing
AKG6N028GL	PDFN5X6	G6N028GL	Tape Reel	See the detail package information

Notes:

1. Contact ALKAIDSEMI sales for detail information

Maximum Ratings (T_A = 25°C unless otherwise noted)

Symbol	Parameter	Value	Units
V _{DS}	Drain-Source Voltage	60	V
I _D	Drain Current - Continuous (T _C = 25°C) ^(Note 1)	100	A
	Drain Current - Continuous (T _C = 100°C)	63	A
I _{DM}	Drain Current - Pulsed ^(Note 2)	400	A
V _{GS}	Gate-Source Voltage	± 20	V
E _{AS}	Single Pulsed Avalanche Energy ^(Note 3)	196	mJ
P _D	Power Dissipation (T _C = 25°C)	62	W
T _J , T _{STG}	Operating and Storage Temperature Range	-55 to +150	°C

Thermal Characteristics

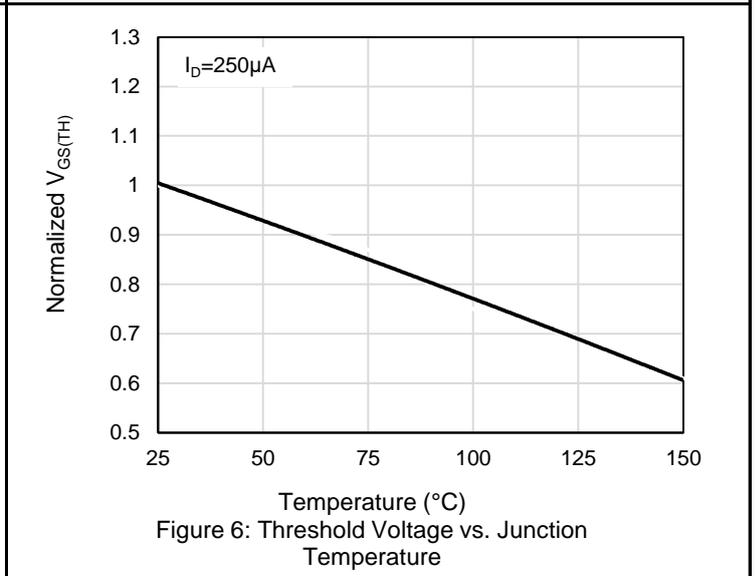
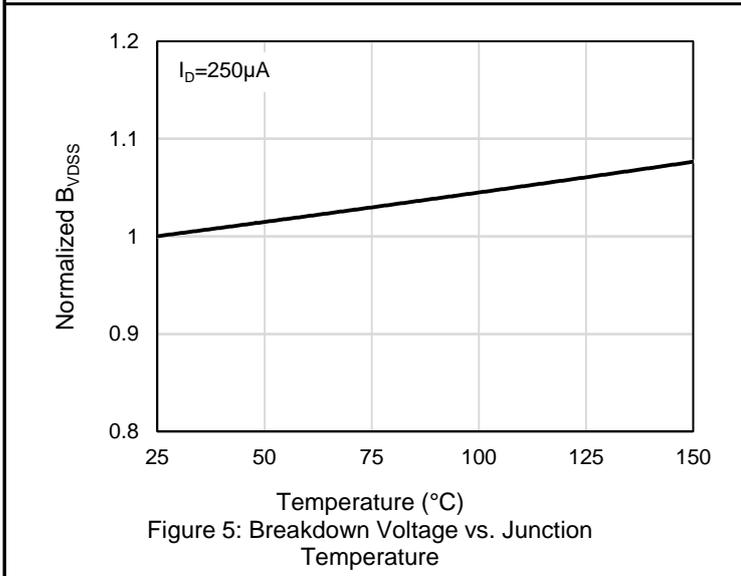
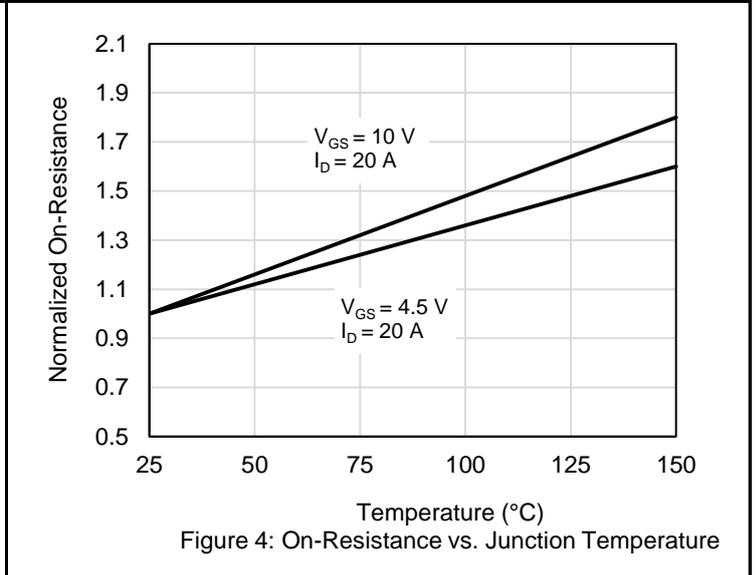
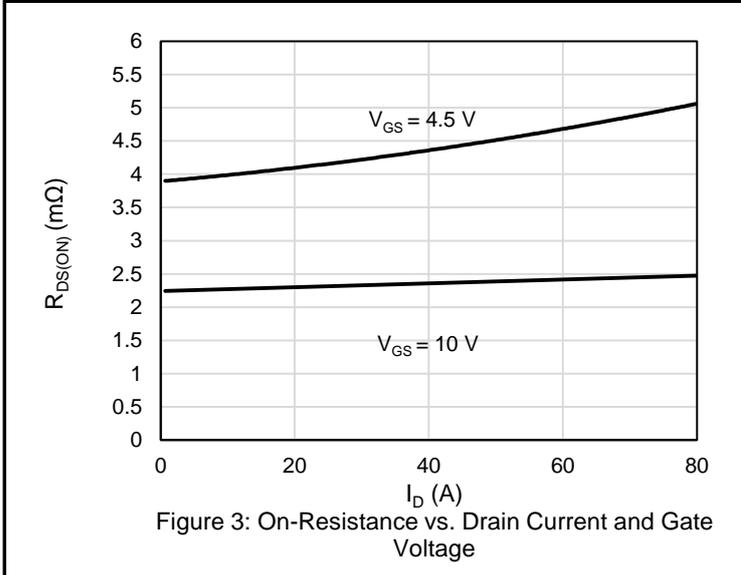
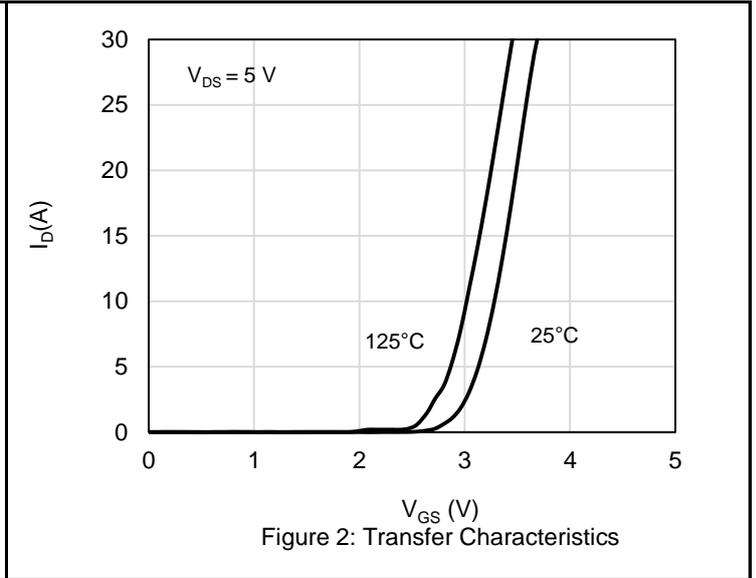
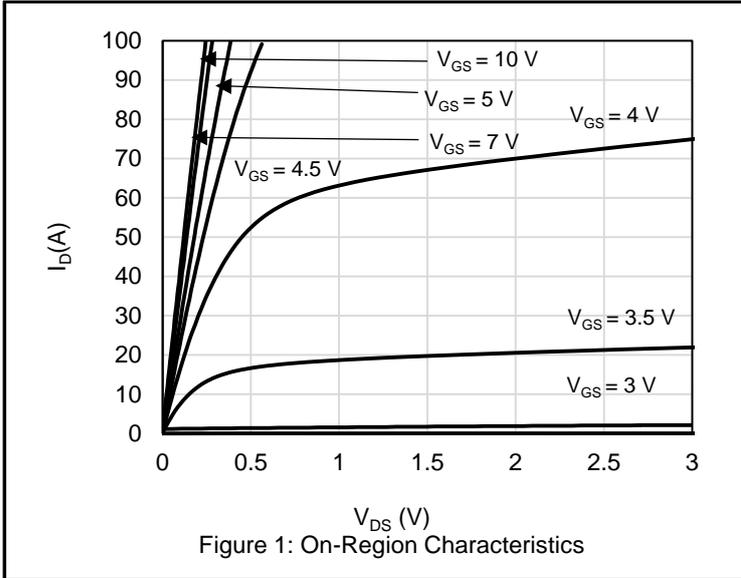
Symbol	Parameter	Value	Units
R _{θJC}	Thermal Resistance, Junction-to-Case, Steady-State	2	°C/W
R _{θJA}	Thermal Resistance, Junction-to-Ambient, Steady State ^(Note 4)	50	°C/W

Notes:

1. The max drain current rating is package limited
2. Repetitive Rating: Pulse width limited by maximum junction temperature
3. L = 0.5 mH, V_{DD} = 30 V, I_{AS} = 28 A, R_G = 25 Ω, Starting T_J = 25 °C
4. Mount on minimum PCB layout

Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise noted)						
Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Static Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = 250\ \mu\text{A}$	60			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 60\text{ V}, V_{GS} = 0\text{ V},$			1	μA
I_{GSS}	Gate Leakage Current	$V_{GS} = \pm 20\text{ V}, V_{DS} = 0\text{ V}$			± 100	nA
$V_{GS(TH)}$	Gate Threshold voltage	$V_{DS} = V_{GS}, I_D = 250\ \mu\text{A}$	1	2	3	V
$R_{DS(ON)}$	Drain-Source on-state resistance	$V_{GS} = 10\text{ V}, I_D = 20\text{ A}$		2.3	2.8	m Ω
		$V_{GS} = 4.5\text{ V}, I_D = 15\text{ A}$		4.1	5.5	m Ω
Dynamic Characteristics						
C_{ISS}	Input Capacitance	$V_{DS} = 30\text{ V}, V_{GS} = 0\text{ V},$ $F = 1\text{ MHz}$		3828		pF
C_{OSS}	Output Capacitance			773		pF
C_{RSS}	Reverse Transfer Capacitance			78		pF
R_G	Gate Resistance	$F = 1\text{ MHz}$		1.1		Ω
Switching Characteristics						
$T_{D(ON)}$	Turn On Delay Time	$V_{DD} = 30\text{ V}, R_L = 1.5\ \Omega,$ $V_{GS} = 10\text{ V}, R_G = 6\ \Omega$		18		ns
T_R	Rise Time			51.0		ns
$T_{D(OFF)}$	Turn Off Delay Time			61.0		ns
T_F	Fall Time			65.5		ns
Q_G	Total Gate Charge	$V_{DD} = 30\text{ V}, I_D = 20\text{ A},$ $V_{GS} = 10\text{ V}$		69.2		nC
Q_{GS}	Gate-Source Charge			11.7		nC
Q_{GD}	Gate-Drain Charge			17.8		nC
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Body-Diode Forward Current				100	A
I_{SM}	Maximum Pulsed Body-Diode Forward Current				400	A
V_{SD}	Diode Forward Voltage	$V_{GS} = 0\text{ V}, I_S = 1\text{ A}$		0.7	1	V
T_{RR}	Reverse recovery time	$V_{DD} = 30\text{ V}, I_D = 20\text{ A},$ $di/dt = 100\text{ A}/\mu\text{s}$		44.5		ns
Q_{RR}	Reverse recovery charge			52.0		nC
I_{RRM}	Peak Reverse Recovery Current			2		A

Electrical Characteristics Diagrams



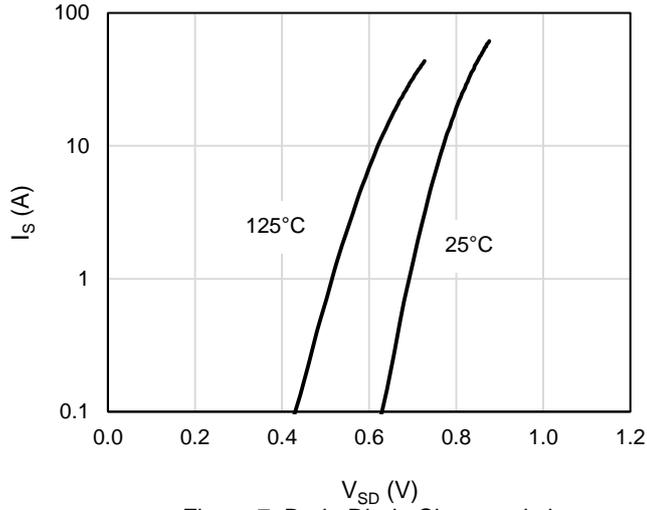


Figure 7: Body-Diode Characteristics

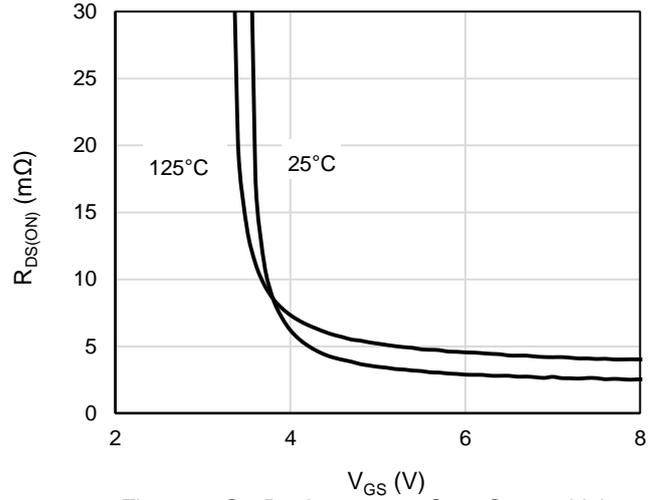


Figure 8: On-Resistance vs. Gate-Source Voltage

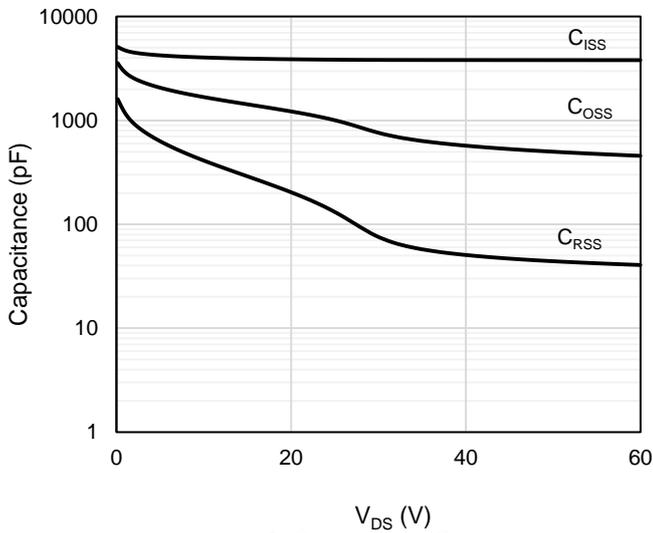


Figure 9: Capacitance Characteristics

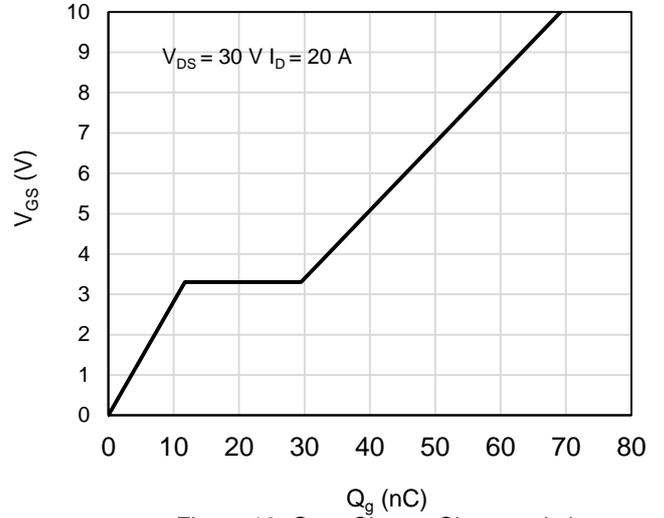


Figure 10: Gate-Charge Characteristics

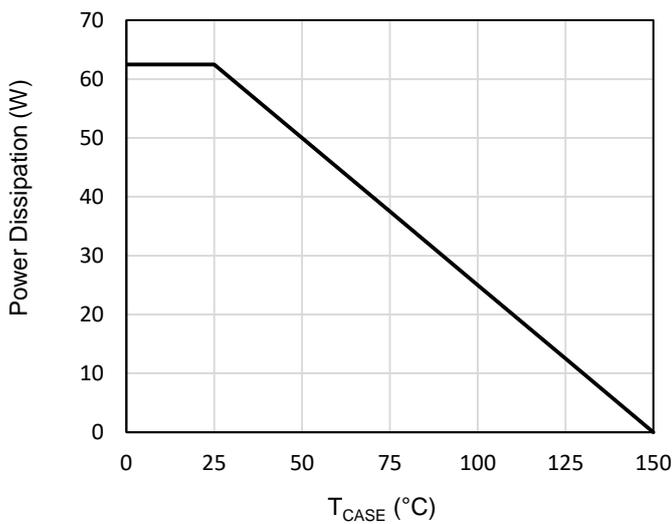


Figure 11: Power De-rating

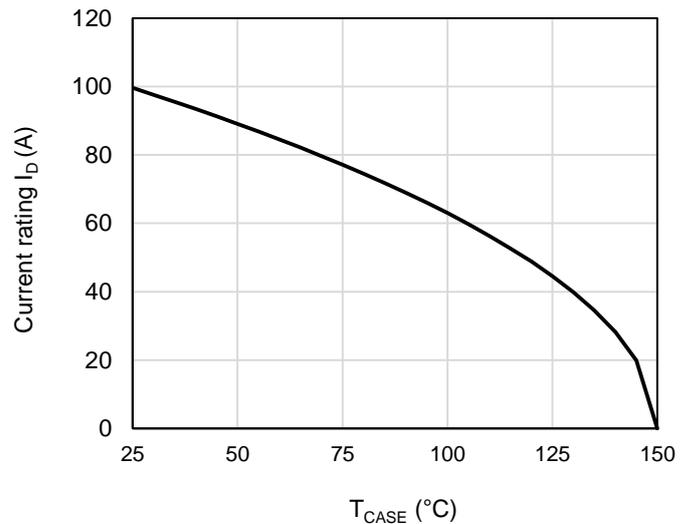
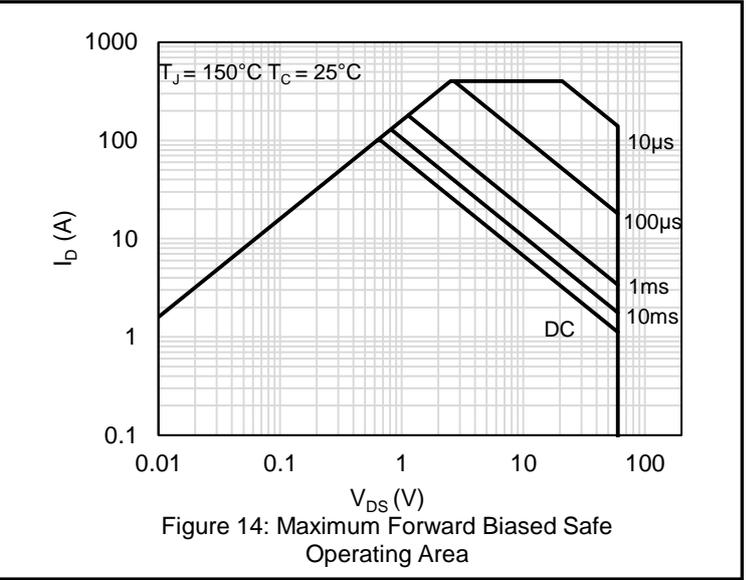
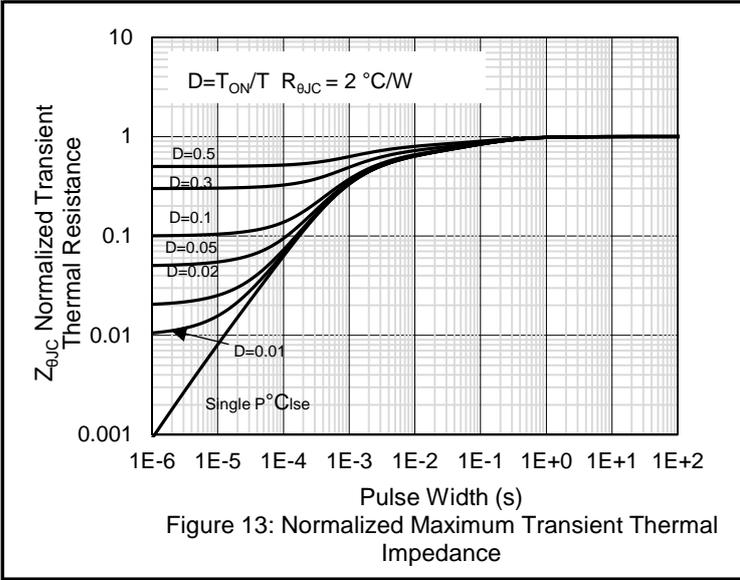
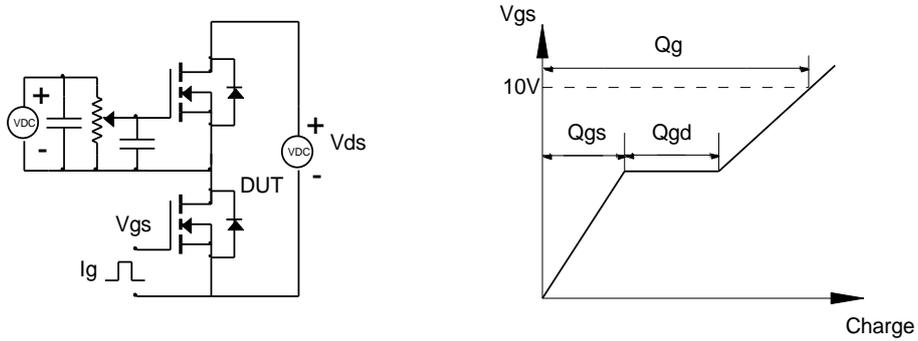


Figure 12: Current De-rating

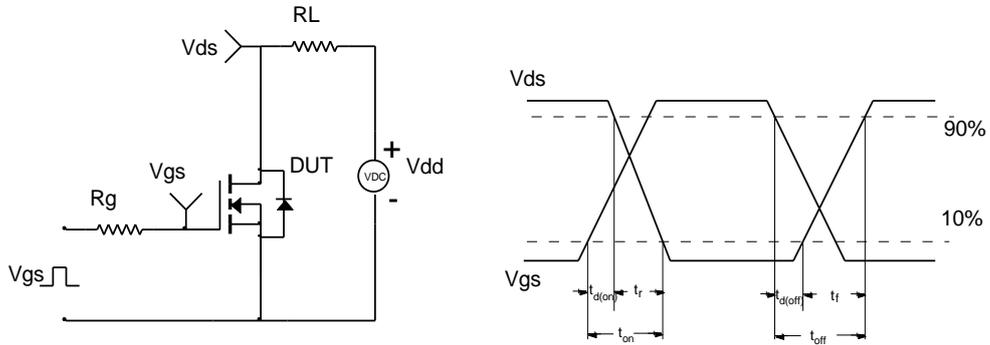


Test Circuit and Waveform

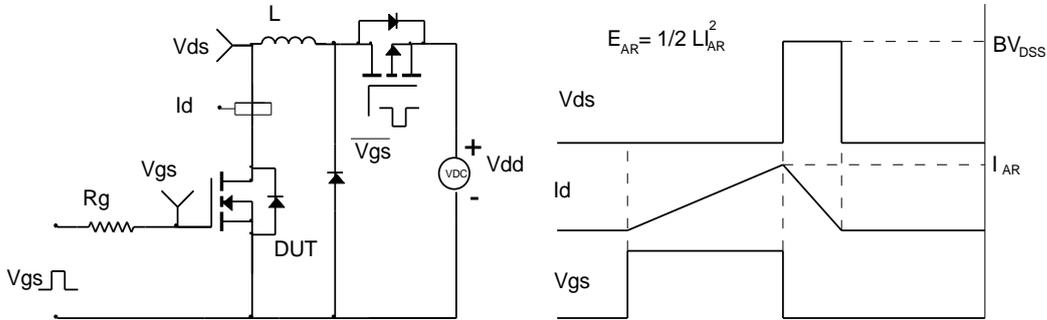
Gate Charge Test Circuit & Waveform



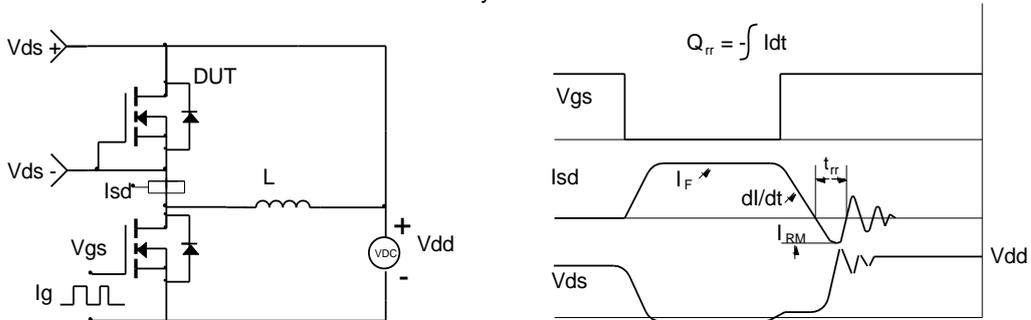
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Revision History

Revision	Release Date	Remark
Rev.1.1	2023/9/11	

Disclaimer

The information given in this document describes the independent performance of the product, but similar performance is not guaranteed under other working conditions, and cannot be guaranteed when installed with other products or equipment. To achieve the required performance of the product in actual scenarios, the customer should conduct a complete application test to assess the functionality of the product.

Alkaidsemi assumes no responsibility for equipment failures result from using products at values that exceed the ratings, operating conditions, or other parameters listed in the product specifications.

The product described in this specification is not applicable for aerospace or other applications which requires high reliability. Customers using or selling these products for use in medical, life-saving, or life-sustaining applications do so at their own risk and agree to fully indemnify.

Due to product or technical improvements, the information described or contained herein may be changed without prior notice.